

Docket No.: W&B-INF-1960

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : ROBERT KAISER ET AL.  
Filed : CONCURRENTLY HERewith  
Title : METHOD FOR COMPARING THE ADDRESS OF A MEMORY  
ACCESS WITH AN ALREADY KNOWN ADDRESS OF A  
FAULTY MEMORY CELL

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

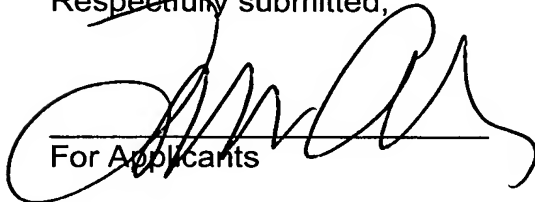
In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent No. 6,115,828 (Tsutsumi et al.), dated September 5, 2000;

Lucente, M. A. et al.: "Memory System Reliability Improvement Through Associative Cache Redundancy", IEEE Journal of Solid State Circuits, Vol. 26, No. 3, March 1991, pages 404-409;

International Search Report, dated August 11, 2003.

Respectfully submitted,

  
For Applicants

Date: October 20, 2003  
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| <b>FORM PTO-1449 (SUBSTITUTE)</b><br><br>U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE<br><br><b>INFORMATION DISCLOSURE<br/>         STATEMENT BY APPLICANT<br/>         (37 CFR 1.98(b))</b> |   |  |        | Attorney Docket No.: W&B-INF-1960<br>Appl. No.: _____<br><br>Applicant: ROBERT KAISER ET AL.<br><br>Filing Date: October 20, 2003<br>Group Art Unit: _____ |       |              |                     |
|  |   |  |        |  |       |              |                     |
| EXAMINER<br>INITIALS   |   | PATENT NO.   | DATE   | PATENTEE   | CLASS | SUB<br>CLASS | FILING<br>DATE      |
|  | A | 6,115,828  | 9/5/00 | Tsutsumi et al.  |       |              |                     |
|  | B |  |        |  |       |              |                     |
|  | C |  |        |  |       |              |                     |
|  | D |  |        |  |       |              |                     |
|  | E |  |        |  |       |              |                     |
|  | F |  |        |  |       |              |                     |
|  | G |  |        |  |       |              |                     |
|  | H |  |        |  |       |              |                     |
|  | I |  |        |  |       |              |                     |
| <b>FOREIGN PATENT DOCUMENT</b>   |   |  |        |  |       |              |                     |
|  |   | DOCUMENT NO.   | DATE   | COUNTRY  | CLASS | SUB<br>CLASS | TRANSL.<br>YES   NO |
|  | J |  |        |  |       |              |                     |
|  | K |  |        |  |       |              |                     |
|  | L |  |        |  |       |              |                     |
|  | M |  |        |  |       |              |                     |
|  | N |  |        |  |       |              |                     |
| <b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>  |   |  |        |  |       |              |                     |
|  |   | Lucente, M. A. et al.: "Memory System Reliability Improvement Through Associative Cache Redundancy", IEEE Journal of Solid State Circuits, Vol. 26, No. 3, March 1991, pages 404-409 |        |  |       |              |                     |
| <b>EXAMINER</b>  |   | <b>DATE CONSIDERED</b>   |        |  |       |              |                     |
|  |   |  |        |  |       |              |                     |